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Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Damian Fiolka et al.		
		Filing Date November 29, 2006	Group Art Unit 2872	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/J.C./	1	7,170,289	1/30/2007	Bievenour et al.			
/J.C./	2	7,433,046 B2	10/7/2008	Everett et al.			
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Foreign Patent Documents or Published Foreign Patent Applications							
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation
							Yes No
/J.C./	4	JP H06-188169	7/8/1994	JPO			X
/J.C./	5	JP 2001-135560	5/18/2001	JPO			X
/J.C./	6	JP 2005-108925	4/21/2005	JPO			Abstract only
/J.C./	7	WO 01/51981 A1	7/19/2001	WIPO			
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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
/J.C./	11	Copy of Chinese Office Action, with English translation, for the corresponding Chinese Application No. 2010-10155323.X, dated January 20, 2011 .
/J.C./	12	Copy of Chinese Office Action, with English translation, for the corresponding Chinese Application No. 2010-10155325.9, dated January 25, 2011 .
/J.C./	13	Copy of Chinese Office Action with English translation, for the corresponding Chinese Application No. 2010-10155335.2, dated March 17, 2011 .
/J.C./	14	Hecht, Optics, Pearson Education Inc. Fourth Edition, 352-355 , 2002.
/J.C./	15	Smith et al., "Benefiting from polarization – effects on high-NA imaging," Optical Microlithography XVII, Proc. of SPIE Vol. 5377, Bellingham, WA, 2004, pages 68-79.

Examiner Signature <i>/Jade Chwasz/</i>	Date Considered <i>06/13/2011</i>
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	